

**Carrier recombination and emission lifetimes in heavily irradiated pad–detectors and their impact on operational characteristics of pin diodes.**

*Monday 23 May 2011 14:20 (20 minutes)*

**Author:** GAUBAS, Eugenijus

**Co-authors:** VAITKUS, Juozas; CEPONIS, T.

**Presenter:** GAUBAS, Eugenijus

**Session Classification:** Defect and Material Characterization